

# APPROVAL SHEET

ITEM: MONOLITHIC MULTILAYER

CERAMIC CAPACITOR

(Thin Layer Large-Capacitance Type)

Approved by customer : (signing or stamping here)							

SAMWHA CAPACITOR CO., LTD.						
Writtern by	Checked by	Approved by				
21-35	Au.	7/-				

2017. 12. 22.



Address : 124, BUK-RI, NAMSA-MYUN YOUNGIN-SI, KYUNGKI-DO, KOREA

Contact : TEL 82-31-332-6441 , FAX 82-31-332-7661

Home page: www.samwha.com

	< SPE	EC S	SUMMARY >						
SAMWHA Part no.		CS1608X7R105K250NRB							
Туре	Thin Layer Large-Capacitance								
Item	Specification	Unit	Test methods and Conditions(Capacitance,IR)						
Capacitance	1	μF							
Capacitance Tolerance	± 10	%	Testing Frequency: 1 ±0.1kHz Testing Voltage: 1 ±0.2Vrms						
Dissipation Factor	Max. 12.5	%							
Insulation Resistance	More than 50	MΩ	Applied the rated voltage for 2 minutes of charging.						
	1.60 ±0.15	L (mm)							
Chip Size	0.80 ±0.10	W (mm)	*Chip size page 2/8						
	0.80 ±0.10	T (mm)	*Characteristics & Test Method page 3/8~5/8						

Enactment :	STANDARD	NO	SW - M - 04B
March 27,1996	MONOLITHIC MULTILAYER	Paga	1 / Q
,	CERAMIC CAPACITOR LEADLESS TYPE	Page	Ι / Ο

#### 1. General Article

Application Range

These specifications refer to the "Monolithic Multilayer Ceramic Capacitors Leadless Type "mainly used to the computer equipment, communication equipment.

\*Caution: Industrial equipment / For the high reliability equipment / LED equipment / Etc.

Please contact sales representatives or product engineers before using the products.

(For details, please refer Page 8)

# 2. General Code

(1) Type Designation

<u>CS</u>	<u>1608</u>	<u>X7R</u>	<u>105</u>	<u>K</u>	<u>250</u>	<u>N</u>	<u>R</u>	В
(1)	(2)	(3)	(4)	(5)	(6)	(7)	(8)	(9)

- 1) Monolithic Multilayer Ceramic Capacitor Leadless Type
- 2) Size Code:

This is expressed in tens of a millimeter.

The first two digits are the length, The last two digits are width.

3) Temperature Coefficient Code

Classification	Code	Temperature Range	Capacitance Tolerance
Class I	C0G	-55 to +125℃	±30 ppm/℃
	X5R	-55 to +85℃	±15%
Class II	X7R	-55 to +125℃	±15%
	Y5V	-30 to +85℃	+22% ~ -82%

#### 4) Capacitance Code(Pico farads):

The nominal Capacitance Value in pF is expressed by three digit numbers.

The first two digits represents significant figures and the last digit denotes the number of zero ex) 104 = 100000 pF

R denotes decimal

8R2 = 8.2 pF

5) Capacitance Tolerance Code

Code	Tolerance
В	± 0.1 pF
С	± 0.25 pF
D	± 0.5 pF
F	± 1.0 %
G	± 2.0 %
J	± 5 %
K	± 10 %

Code	Tolerance
М	± 20 %
Р	+ 100, -0%
Z	+ 80, -20%
Н	+ 0.25/-0 pF
I	+ 0/-0.25 pF
U	+ 5/-0 %
V	+ 0/-5 %

#### 6) Voltage Code

_													
code	6R3	100	160	250	500	101	201	251	501	631	102	202	302
Val	DC	DC	DC	DC	DC	DC	DC	DC	DC	DC	DC	DC	DC
Vol.	6.3V	10V	16V	25V	50V	100V	200V	250V	500V	630V	1KV	2KV	3KV

#### 7) Termination Code

ex) N: Ni-Sn (Nickel-Tin Plate)

A: Ag/Ni-Sn (Ag Epoxy/Nickel-Tin Plate)

#### 8) Packing Code

ex) R: 7" Reel Type L: 13" Reel Type B: Bulk Type

#### 9) Thickness option (Cu, Ag Epoxy)

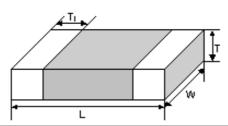
Thickness(mm)		Code	Thickne	ss(mm)	Code
t	Tol(±)	Oode	t	Tol(±)	Oode
0.30	0.03	Blank	1.30	0.20	Е
0.50	0.05	Blank	1.35	0.20	Н
0.60	0.10	А	1.60	0.20	1
0.80	0.10	В	1.80	0.20	J
0.85	0.15	В	2.00	0.25	K
1.00	0.15	Е	2.50	0.25	L
1.10	0.15	Е	2.80	0.30	M
1.15	0.15	Е	3.20	0.30	N
1.25	0.15	Е	5.00	0.40	0

# 3. Temperature Characteristics

See Page 5/8 (No.13)

## 4. Constructions and Dimensions

(I) Dimensions



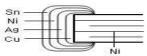
(Unit: mm)

Codo		Len	gth	Wi			
Code	1	Cu	Ag E	роху	Cu, Ag	T1(min)	
	L	Tol(±)	Tol(-)	Tol(+)	W	Tol(±)	
0603	0.60	0.03	_	_	0.30	0.03	0.05
1005	1.00	0.05	0.05	0.10	0.50	0.05	0.05
1608	1.60	0.15	0.15	0.20	0.80	0.10	0.10
2012	2.00	0.20	0.20	0.30	1.25	0.15	0.10
3216	3.20	0.30	0.30	0.40	1.60	0.20	0.15
3225	3.20	0.40	0.40	0.40	2.50	0.25	0.15
4520	4.50	0.40	0.40	0.40	2.00	0.25	0.20
4532	4.50	0.40	0.40	0.40	3.20	0.30	0.20
5750	5.70	0.50	0.50	0.50	5.00	0.40	0.30

\*2012 Size ≥10 $\mu$ F ⇒ W: 1.25±0.20, T: 0.85±0.15 \*3216 Size ≥47 $\mu$ F ⇒ W: 1.60±0.30, T: 1.60±0.30

# (2) Construction of Termination







(Inner Electrode: Ni Type I) (Inner Electrode: Ni Type II) (Inner Electrode: Ag/pd Type)

SW - M - 04B 3 / 8

# Specifications and Test Methods (Thin Layer Large-Capacitance Type)

No.	Item		Specification	Test Methods and Conditions				
1	Operating Temperature Range		X7R : -55 to +125℃ X5R : -55 to +85℃ Y5V : -30 to +85℃					
2	Insulation Resistance		50Ω·F min	·Applied the rated voltage for 2 minutes of charging, The charge/discharge current is less than 50mA.				
3	Dielectric Str	rength	No defects or abnormalities	X7R, X5R, Y5V: The rated voltage × 250%  - Applied between the terminations for 1 to 5 seconds.  - The charge/discharge current is less than 50mA.				
4	Capacitance		within the specified tolerance	The capacitance/D.F. should be measured at 25°C at the				
5			X7R, X5R: 12.5%max *3216 Size 100 <sub>4</sub> F: 15%max Y5V: 20%max	frequency and voltage shown in the table.				
				according to Note1 for Class II  · Measurement after test  Take it out and set it for 24±2 hours (Class II)  then measure				
6			-Termination should be covered with more than 75% of new solder	*Pb-Free type Solder: 96.5Sn-3Ag-0.5Cu Solder temperature: 245±5°C Immersion time: 3±0.1sec				
		Appearance	No marking defects	*Pre-Heating: at 80~120°C for 10~30sec  Preheat the capacitor at 120 to 150°C for 1 minute.  (Preheating for 3225,4520,4532				
	Resistance	Capacitance change	X7R, X5R: Within±7.5% Y5V: Within±20%	Step1:100°C to 120°C, 1min Step2:170°C to 200°C, 1min  Immerse the capacitor in a eutectic solder solution at				
7	to Soldering Heat	Dissipation Factor	X7R, X5R : 12.5%max *3216 Size 100 <sub>\(\mu\)</sub> F : 15%max Y5V : 20%max	-260±5℃ for 10±0.5 seconds.  Initial measurement Perform the initial measurement according to Note1 for				
		I.R.	50Ω·F min	Class II  Measurement after test Let sit at room temperature for 24±2 hours,then measure.				
		Appearance	No marking defects	Perform the five cycles according to the four heat treatments listed in the following table.				
		Capacitance Change	X7R, X5R: Within ±7.5% Y5V: Within ±20%	Step 1 2 3 4  Min. Temp operating Room operating Room				
8	Temperature D Cycle Fa	Dissipation Factor	X7R, X5R: 12.5%max *3216 Size 100 <sub>\(\mu\)</sub> F: 15%max Y5V: 20%max	(°C)     temp.     Temp     temp.     Temp       +0/-3     +3/-0     +3/-0       Time     30±3     2 to3     30±3     2 to3				
		I.R	50Ω·F min	·Initial measurement Perform the initial measurement according to Note1 for Class II ·Measurement after test Perform the final measurement according to Note2				

No.	o. Item		Specification	Test Methods and Conditions				
9	High Temperature Load	Capacitance Change	No marking defects  X7R, X5R: Within ±12.5% Y5V: Within ±30%  X7R, X5R: 20%max	Apply 150% of the rated voltage for 1000+48/-0 hrs at the maximum operating temperature ±3°C. The charge/discharge current is less than 50mA.  -Initial measurement Perform the initial measurement according				
3		Dissipation Factor	*3216 Size 100μF: 30%max Y5V: 40%max 12.5Ω·F min	to Note1 for Class II  - Measurement after test Perform the final measurement according to Note2				
10	Bending strength	Capacitance Change	P R230    R230   Imm   45mm	·Substrate material : Glass EPOXY Board.  ·Thickness : 1.6mm				
11	Vibration Resistance	Capacitance	No defects or abnormalities  Whin the specified tolerance  X7R, X5R: 12.5%max *3216 Size 100µF: 15%max Y5V: 20%max	*Shown in Fig. After soldering and then let sit for 24±2hr at room temperature. The capacitor should be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz, shall be traversed(from 10Hz to 55Hz then 10Hz again) in approximately 1 minute. This motion shall be applied for a period of 2 hours in each 3mutually perpendicular				
12	Humidity Load		No marking defects  X7R, X5R: Within ±12.5% Y5V : Within ±30%  X7R, X5R : 20%max *3216 Size 100μF : 30%max Y5V : 40%max  12.5Ω·F min	Apply the rated voltage at 40±2°C and 90 to 95%RH for 500+24/-0 hrs. The charge/discharge current is less than 50mA.  Initial measurement Perform the initial measurement according to Note1 for Class II  Measurement after test Perform the final measurement according to Note2				

١	lo.	ltem	Specification					Test Methods and Conditions			
	13	Capacitance Temperature Characteristics	Char. X5R X7R Y5V	Temp. Range  -55 to +85°C  -55 to +125°C  -30 to +85°C	Reference Temp. 25°C 25°C	Within	Change ±15% ±15% +22/-82%	The capacitance change should be measured after 5 min. at each specified temperature stage.  The ranges of capacitance change compared with the 25°C value over the temperature ranges shown in the table should be within the specified ranges.			

#### \*Note1. Initial Measurement for Class II

Perform a heat treatment at 150+0,-10°C for one hour and then let sit for 24±2 hours at room temperature, then measure

#### \*Note2. Measurement after test

Class I

Perform a heat treatment at 150+0,-10°C for one hour and then let sit for 24±2 hours at room temperature, then measure.

# 5. Packing

- (1) Bulk packing
  - 1 1000 pcs per Polybag
  - 2 5 Polybags per Inner box
  - 3 10 Inner boxes per Out box
- (2) Reel Packing
  - ① 8~10 Reels per Inner box
  - 2 6 Inner boxes per Out box
- (3) Reel Dimensions



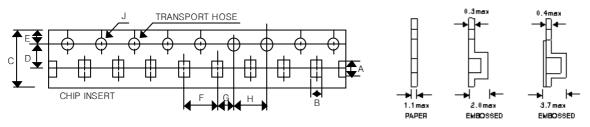


	(Unit : m							
MARK	SIZE	Α	В	С	D	E	W	
7 " REEL	0603~3225	Φ178±2	Ф50Min	Ф13±0.5	Φ21±0.8	2±0.5	10±1.5	
/ REEL	4520~4532	Ф180+0,-3	Ф60-0,+1	Φ13±0.2	Ф57-0+1	3±0.2	13±0.5	
13 " REEL	1005~3225	Ф330±2	Φ70Min	Ф13±0.5	Φ21±0.8	2±0.5	10±1.5	

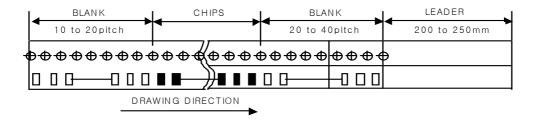
#### (4) Number of Package

TYPF	EIA CODE	7"	13"		
ITE	EIA CODE	Qt/REEL	Qt/REEL		
CS0603	CC0201	15,000			
CS1005	CC0402	10,000	50,000		
CS1608	CC0603	4,000	16,000		
CS2012	CC0805	3,000 ~ 4,000	10,000		
CS3216	CC1206	2,000 ~ 4,000	6,000 ~ 10,000		
CS3225	CC1210	1,000 ~ 3,000	4,000 ~ 10,000		
CS4520	CC1808	1,500 ~ 3,000	_		
CS4532	CC1812	500 ~ 1,000	1,500 ~ 5,000		

## (5) Tape Dimensions



TYPE	EIA CODE	А	В	С	D	Е	F	G	Н	J
CS0603	CC0201	0.67±0.05	0.37±0.05	8.0±0.3	3.5±0.05	1.75±0.1	2.0±0.05	2.0±0.1	4.0±0.1	1.5±0.1
CS1005	CC0402	1.15±0.1	0.65±0.1	8.0±0.3	3.5±0.05	1.75±0.1	2.0±0.05	2.0±0.1	4.0±0.1	1.5±0.1
CS1608	CC0603	1.9±0.2	1.10±0.2	8.0±0.3	3.5±0.05	1.75±0.1	4.0±0.1	2.0±0.1	4.0±0.1	1.5±0.1
CS2012	CC0805	2.4±0.2	1.65±0.2	8.0±0.3	3.5±0.05	1.75±0.1	4.0±0.1	2.0±0.1	4.0±0.1	1.5±0.1
CS3216	CC1206	3.6±0.2	2.00±0.2	8.0±0.3	3.5±0.05	1.75±0.1	4.0±0.1	2.0±0.1	4.0±0.1	1.5±0.1
CS3225	CC1210	3.6±0.2	2.80±0.2	8.0±0.3	3.5±0.05	1.75±0.1	4.0±0.1	2.0±0.1	4.0±0.1	1.5±0.1
CS4520	CC1808	4.8±0.2	2.3±0.2	12.0±0.3	5.5±0.1	1.75±0.1	4.0±0.1 8.0±0.1	2.0±0.1	4.0±0.1	1.5±0.1
CS4532	CC1812	4.9±0.2	3.6±0.2	12.0±0.3	5.5±0.1	1.75±0.1	8.0±0.1	2.0±0.1	4.0±0.1	1.5±0.1



#### 6.Caution

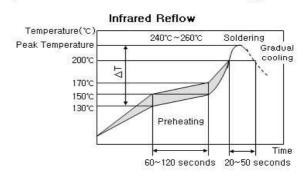
#### ► Reflow Soldering

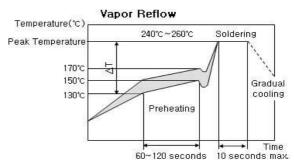
- 1. The sudden temperature change easily causes mechanical damages to ceramic components. Therefore, the preheating procedures should be required for the soldering of ceramic components.
- 2. Please refer to the recommended soldering profiles as shown in figures, and keep the temperature difference  $(\triangle T)$ within the range recommended in Table 1.

#### Table 1

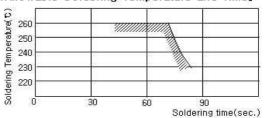
Size code	Temperature Difference
0603, 1005, 1608, 2012, 3216	△T≤190°C
3225size and over	△T≤130°C

#### [Standard Conditions for Reflow Soldering]





#### [Allowable Soldering Temperature and Time]



In case of repeated soldering, the accumulated soldering time must be within the range shown above.

#### ► Storage Condition

\*When Solderability is considered, Capacitor are recommended to be used in 12 months

(1) Temperature:  $25^{\circ}$ C ±  $10^{\circ}$ C

(2) Relative Humidity: Below 70% RH

▶ The Regulation of Environmental Pollution Materials.

\*Never use materials mentioned below in MLCC products regulated this document.

Pb, Cd, Hg, Cr<sup>+6</sup>, PBB(Polybromide biphenyl), PBDE(Polybrominated diphenyl ethers), asbestos.

#### Note

#### (1) 'Aging'/'De-aging' Behavior of high dielectric MLCCs

(Typically represented by X7R, Y5V temperature characteristic of which main composition is BaTiO3)

'Aging' / 'De-aging' Behavior of high dielectric MLCCs Please note that high dielectric type dielectric Ceramic Capacitors have a "normal" 'aging' behavior / characteristic, that is; their capacitance value decreases with time from its value when it was first manufactured. From that date, the capacitance value begins to decrease at a logarithmic rate defined by:

$$C_t = C_{24} (1 - k \log 10 t)$$

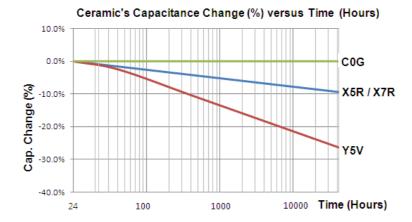
where:

Ct = Capacitance Value, t hours after the start of 'aging'

C<sub>24</sub> = Capacitance Value, 24 hours after its manufacture

k = aging constant ( capacitance decrease per decade-hour )

t = time, in hours, from the start of 'aging'



The capacitance value can be restored (a.k.a. 'de-aged') by exposing the component to elevated temperatures approaching its Curie Temperature (approximately  $120\,^{\circ}$ C). This 'deaging' can occur during the component's solder-assembly onto the PCB, during life or temperature cycle testing., or by 'baking' at  $150\,^{\circ}$ C for about 1 hour.

Dielectric	Maximum Percent Capacitance Loss per Decade hour, k
COG	0
X5R/X7R	~3%
Y5V	~8%

- (2) Please contact our sales representatives or product engineers before using the products in this catalog for the applications listed below, which require especially high reliability for the prevention of defects which might directly damage a third party's life, body or property, or when one of our products is intended for use in applications other than those specified in this catalog.
  - ①Aircraft equipment
- ②Aerospace equipment
- ③Undersea equipment

- ©Transportation equipment (vehicles, trains, ships, etc.)
- Traffic signal equipment & Disaster prevention / crime prevention equipment
- Industrial equipment (Conveyors, Robot equipment, etc)Application of similar complexity and/or reliability requirements to the applications listed above